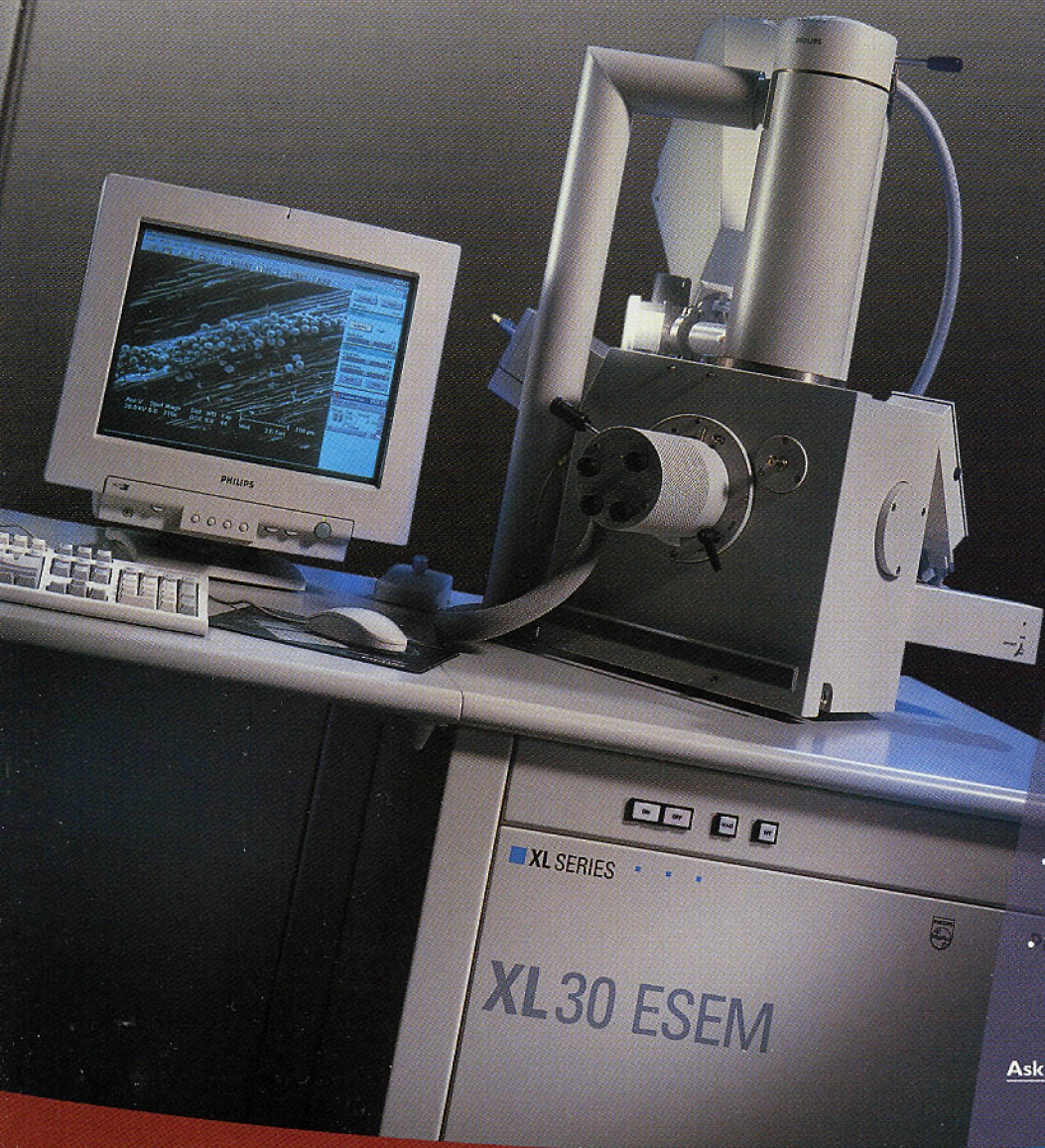




XL30

Exceed your Low-Vac SEM expectations



When you look at specifications you'll quickly find that all LV SEMs are not the same. The XL30 ESEM is our Low Vac SEM and is the affordable solution to your Low Vac SEM needs.

Check out our added value:

- Superior surface detail low kV imaging, in both Hi Vac and Low Vac
- Same High resolution specifications in all modes of operation
- Uncoated sample exploration with both SE and BSE at full field of view
- Clean column conditions when imaging dirty samples
- The ability to acquire quantitative EDS results without coating and going to Hi Vac

Ask us to show you!



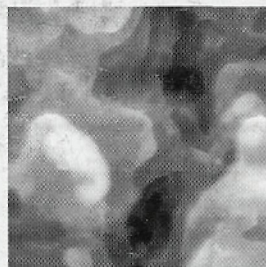
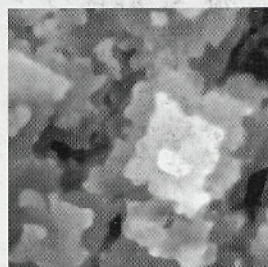
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PHILIPS

Let's make things better.

As Easy As It Looks



PEO at 60°C with evidence of melting clearly shown after 2 minutes.

- ▶ **Based on a Simple PC Interface.**
- ▶ **Intuitive Operation with a Mouse Alone.**
- ▶ **Capable of Imaging Under Either Ambient or High Vacuum and at Both High and Low Temperatures.**
- ▶ **Fully Vibrationally Isolated.**
- ▶ **Capable of Wet or Dry Imaging.**
- ▶ **Variable Gas Pressure/Temperature.**

The new JSPM-4200 is a multipurpose turnkey Scanning Probe Microscope (SPM) capable of imaging using a myriad of different modes and

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NEW - Multi-Environmental

SPM

Scanning Probe Microscope

accessories. Imaging modes include STM, STS (Scanning Tunneling Spectroscopy), CITS (Current Imaging Tunneling Microscopy), AFM, LFM (Lateral Force Microscopy), Non-contact Mode AFM, Discrete Contact Mode AFM, Lateral Modulation LFM, MFM (Magnetic Force Microscopy), and Force Modulation Microscopy.

If you would like to learn more about JEOL SPM's please give us a call and arrange for your own hands-on demonstration so that we can prove to you that it really is "As Easy As It looks".

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